

Search Notes

Application/Control No.

10/617,826

Examiner

Leon J. Harper

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner
707	10,104.1, 100	1/4/2006	LJH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR